

TEST REPORT (시 험 성 적 서)

신청기관 (인) : 삼화콘덴서

APPLICANT : SAMWHA CAPACITOR Co., Ltd.

주소 (한글) :경기도 용인시 남사면 경기동로 227

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발행면수 (PAGE):1 of 9

발행일자 (DATE): 2020. 03. 17.

시험성적서 번호 (REPORT NO.):RT20R-S1139-001-K

시료 명세 :시료에 대한 상세한 정보는 아래와 같음 (SAMPLE DESCRIPTION) (The following submitted sample(s) said to be)

제품명/형식 : CHIP BEAD (NAME/TYPE OF PRODUCT) (CHIP BEAD)

재질 : Ferrite (NAME OF MATERIAL) : Ferrite

시료고유번호 : RT20R-S1139-001 (SAMPLE ID NO.) (RT20R-S1139-001)

품번 : CB (ITEM NO.) (CB)

제품 생산자/공급자 : 삼화콘덴서

(MANUFACTURER/VENDOR) (SAMWHA CAPACITOR Co., Ltd.)

제출처 : SAMSUNG, LG, Hynix (NAME OF BUYER) (SAMSUNG, LG, Hynix)

시료접수일자 : 2020. 03. 11. (SAMPLE RECEIVED) (Mar. 11, 2020)

시험일자 : 2020. 03. 11. ~ 2020. 03. 17. (TESTING DATE) : (Mar. 11, 2020 ~ Mar. 17, 2020)

시험방법 : 이 시험성적서의 다음 페이지 첨부

(TEST METHOD) (Please see the following page)

시험결과 : 이 시험성적서의 다음 페이지 첨부

(TEST RESULT) (Please see the following page)

비고 (Notes): 1. 이 시험성적서는 제시된 시료 및 시료명으로 시험한 결과로서 유사 대상시료에 적용할 수 없음.

(The test results presented in this report refer only to the object tested.)

2. 이 시험성적서는 승인없이 복사 사용을 금함.

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3. 이 시험성적서의 품번은 고객의 요청 및 보증서에 의거하여 명기함.

(The item no. is assigned by client and indicated according to their requirement and guarantee letter.)

승인자 (Approved by)

권한자 (Authorized by)

박병옥/소장

(Bo Park / Lab. General Manager)

장준용/기술책임자

(Jade Jang / Lab. Technical Manager)

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Authenticity check









(시 험 성 적 서)

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시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 발행일자 (DATE): 2020. 03. 17.

시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001 시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

시험항목	단위	분석방법	검출한계	시험결과
(TEST ITEM)	(UNIT)	(TEST METHOD)	(MDL)	(RESULT)
카드뮴 (Cadmium, Cd)	mg/kg	With reference to IEC 62321-5 Edition 1.0 : 2013,	0.5	N.D.
납 (Lead, Pb)	mg/kg	by acid digestion and determined by ICP-OES	5	N.D.
수은 (Mercury, Hg)	mg/kg	With reference to IEC 62321-4 Edition 1.0 : 2013, by acid digestion and determined by ICP-OES	2	N.D.
6가 크롬 (Hexavalent Chromium, Cr ⁶⁺)	mg/kg	With reference to IEC 62321-7-2 Edition 1.0 : 2017, by alkaline/toluene digestion and determined by UV-VIS Spectrophotometer	8	N.D.
폴리브롬화비페닐 (Polybrominated Biphen	yls, PBBs)			
모노브로모비페닐 (MonoBB)	mg/kg		5	N.D.
다이브로모비페닐 (DiBB)	mg/kg		5	N.D.
트라이브로모비페닐 (TriBB)	mg/kg		5	N.D.
테트라브로모비페닐 (TertaBB)	mg/kg	With reference to	5	N.D.
펜타브로모비페닐 (PentaBB)	mg/kg	IEC 62321-6 Edition 1.0 : 2015,	5	N.D.
헥사브로모비페닐 (HexaBB)	mg/kg	by solvent extraction and	5	N.D.
헵타브로모비페닐 (HeptaBB)	mg/kg	determined by GC/MS	5	N.D.
옥타브로모비페닐 (OctaBB)	mg/kg		5	N.D.
노나브로모비페닐 (NonaBB)	mg/kg		5	N.D.
데카브로모비페닐 (DecaBB)	mg/kg		5	N.D.
폴리브롬화디페닐에테르 (Polybrominated	Diphenyl Ether	rs, PBDEs)		
모노브로모디페닐에테르 (MonoBDE)	mg/kg		5	N.D.
다이브로모디페닐에테르 (DiBDE)	mg/kg		5	N.D.
트라이브로모디페닐에테르 (TriBDE)	mg/kg		5	N.D.
테트라브로모디페닐에테르 (TetraBDE)	mg/kg	With reference to	5	N.D.
펜타브로모디페닐에테르 (PentaBDE)	mg/kg	IEC 62321-6 Edition 1.0 : 2015,	5	N.D.
헥사브로모디페닐에테르 (HexaBDE)	mg/kg	by solvent extraction and	5	N.D.
헵타브로모디페닐에테르 (HeptaBDE)	mg/kg	determined by GC/MS	5	N.D.
옥타브로모디페닐에테르 (OctaBDE)	mg/kg		5	N.D.
노나브로모디페닐에테르 (NonaBDE)	mg/kg		5	N.D.
데카브로모디페닐에테르 (DecaBDE)	mg/kg		5	N.D.

Tested by: Jooyeon Lee, Seulgi Park, Miseon Lee

Notes: mg/kg = ppm = parts per million (함량 표시 : 백만분의 일)

< = Less than (결과 값 이하)

N.D. = Not detected (< MDL, 미검출 – 검출한계 이하)

MDL = Method detection limit (검출한계)

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(시 험 성 적 서)

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시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 발행일자 (DATE): 2020. 03. 17.

시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001 시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

(CIIII DEAD)					
시험항목	단위	분석방법	검출한계	시험결과	
(TEST ITEM)	(UNIT)	(UNIT) (TEST METHOD)		(RESULT)	
브롬 (Bromine, Br)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	N.D.	
염소 (Chlorine, Cl)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	139	
플루오르 (Fluorine, F)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	94	
요오드 (Iodine, I)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	N.D.	
베릴륨 (Beryllium, Be)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.	
안티몬 (Antimony, Sb)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.	

Tested by : Hyojoo Kim, Jooyeon Lee

Notes: mg/kg = ppm = parts per million (함량 표시 : 백만분의 일)

< = Less than (결과 값 이하)

N.D. = Not detected (< MDL, 미검출 – 검출한계 이하)

MDL = Method detection limit (검출한계)

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(시 험 성 적 서)

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시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 발행일자 (DATE): 2020. 03. 17.

시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001 시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

시험항목	CAS번호	단위	분석방법	검출한계	시험결과
(TEST ITEM)	(CAS NO.)	근표 (UNIT)	문역장됩 (TEST METHOD)	검찰인계 (MDL)	시험설피 (RESULT)
디부틸프탈레이트 (Dibutyl phthalate, DBP)	84-74-2	mg/kg		50	N.D.
디에틸헥실프탈레이트 (Di-(2-ethylhexyl) phthalate, DEHP)	117-81-7	mg/kg		50	N.D.
디엔옥틸프탈레이트 (Di-n-octyl phthalate, DNOP)	117-84-0	mg/kg		50	N.D.
디이소노닐프탈레이트 (Diisononyl phthalate, DINP)	28553-12-0 68515-48-0	mg/kg		100	N.D.
디이소데실프탈레이트 (Diisodecyl phthalate, DIDP)	26761-40-0 68515-49-1	mg/kg		100	N.D.
벤질부틸프탈레이트 (Benzyl butyl phthalate, BBP)	85-68-7	mg/kg	With reference to IEC 62321-8 Edition 1.0 : 2017,	50	N.D.
디이소부틸프탈레이트 (Diisobutyl phthalate, DIBP)	84-69-5	mg/kg	by solvent extraction and determined by GC/MS	50	N.D.
디엔펜틸프탈레이트 (Di-n-pentyl phthalate, DPP)	131-18-0	mg/kg	GC/W3	50	N.D.
디엔헥실프탈레이트 (Di-n-hexyl phthalate, DNHP)	84-75-3	mg/kg		50	N.D.
디(2-메톡시에틸)프탈레이트 (Di(2-methoxyethyl) phthalate, DMEP)	117-82-8	mg/kg		50	N.D.
디이소펜틸프탈레이트 (Diisopentylphthalate, DIPP)	605-50-5	mg/kg		50	N.D.
엔펜틸이소펜틸프탈레이트 (N-pentyl-isopentylphthalate, NPIP)	776297-69-9	mg/kg		50	N.D.

Tested by : Miseon Lee

Notes: mg/kg = ppm = parts per million (함량 표시 : 백만분의 일)

<= Less than (결과 값 이하)

N.D. = Not detected (< MDL, 미검출 - 검출한계 이하)

MDL = Method detection limit (검출한계)

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발행면수 (PAGE): 5 of 9 발행일자 (DATE): 2020.03.17.

시험성적서 <u>번호 (REPORT NO.)</u>: RT20R-S1139-001-K

시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001 시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

* 시료 접수 시 시료 상태 : (View of sample as received)



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(시 험 성 적 서)

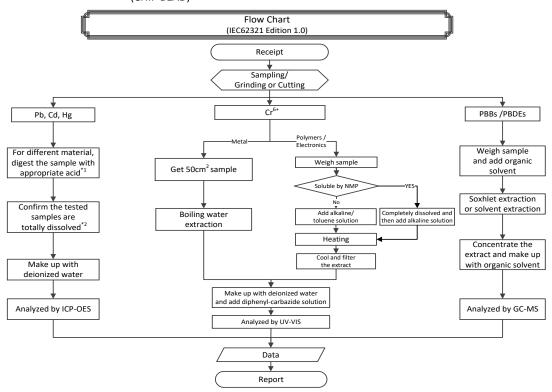
발행면수 (PAGE):6 of 9

발행일자 (DATE): 2020.03.17.

시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001

시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)



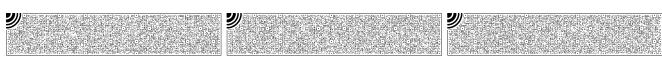
Remarks: *1: List of appropriate acid:

٠,	ist of appropriate acid.	
	Material	Acid added for digestion
	Polymers	HNO ₃ , HCl, HF, H ₂ O ₂ , H3BO ₃
	Metals	HNO₃, HCl, HF
	Electronics	HNO ₃ , HCl, H ₂ O ₂ , HBF ₄

^{*2 :} The samples were dissolved totally by pre-conditioning method according to above flow chart.

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(시 험 성 적 서)

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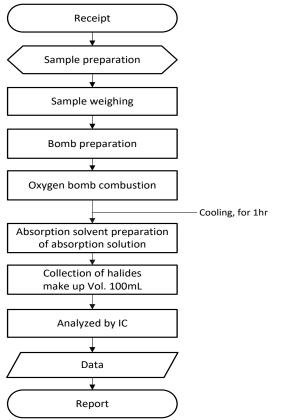
발행일자 (DATE) : 2020. 03. 17.

시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 시료고유번호 (SAMPLE ID NO.): RT20R-S1139-001

시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

Flow Chart (EN14582)



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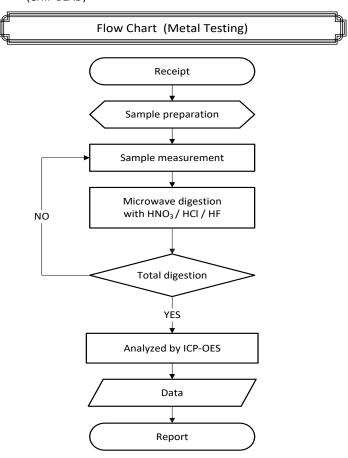
(시 험 성 적 서)

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시험성적서 번호 (REPORT NO.): RT20R-S1139-001-K 발행일자 (DATE): 2020. 03. 17.

시료고유번호 (SAMPLE ID NO.) : RT20R-S1139-001 시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)



** 비고 : 이 샘플은 위의 흐름도에 따른 전처리 방법에 의해 완전용해 되었음. (The samples were dissolved totally by pre-conditioning method according to above flow chart.)

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(시 험 성 적 서)

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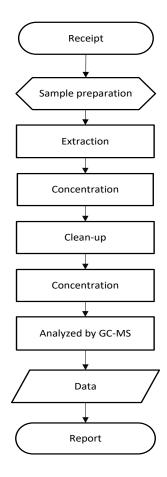
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시료명 (SAMPLE DESCRIPTION) : CHIP BEAD

(CHIP BEAD)

Flow Chart (Phthalates)



***** End of Report *****

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